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PATENT
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS : Victor HIGGS; Freddie YUN HENG CHIN; Michael Sweeney;
and Ian Christopher MAYES

APPLICATION NO. : PCT/GB97/02388 ✓

FILED : September 5, 1997

FOR : APPARATUS AND METHOD FOR DETECTING MICRO
DEFECTS IN SEMI-CONDUCTORS

PRELIMINARY AMENDMENT

ASSISTANT COMMISSIONER FOR PATENTS
BOX PCT
WASHINGTON, D.C. 20231

Sir:

Prior to calculating the fees pursuant to the entry into the National Phase of the above-identified Application, please amend the claims as follows:

IN THE CLAIMS:

In Claim 3, line 1, please delete "~~Claims 1 or 2~~" and insert --Claim 1--.

In Claim 4, line 1, please delete "~~any proceeding~~";
line 1, after "claim", insert --1,--.

In Claim 8, line 1, please delete "~~Claims 5-7~~" and insert --Claim 5--.

In Claim 9, line 1, please delete "~~Claims 5-8~~" and insert --Claim 5--.

In Claim 10, line 1, please delete "~~Claims 5-9~~" and insert --Claim 5--.